Search	Notes

Application/Control No.	Applicant(s)/Paten Reexamination	t under
09/709,323	FAY ET AL.	
Examiner	Art Unit	
Susanna M. Diaz	3623	

	SEAR	CHED	
Class	Subclass	Date	Examiner
705	7	1/7/2006	SMD

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